

## **CERTIFICATE OF ELECTRONIC TRANSMISSION**

I hereby certify that this correspondence for Patent No. 7,193,222 is being electronically transmitted to the U.S. Patent and Trademark Office, via EFS-WEB, on May 21, 2007.

/William R. Allen/  
William R. Allen, Reg. No. 48,389

May 21, 2007  
Date

**PATENT**

### **IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent of: Jacka et al.  
Patent No.: 7,193,222  
Issue Date: March 20, 2007  
Title: SECONDARY ELECTRON DETECTOR, ESPECIALLY IN A  
SCANNING ELECTRON MICROSCOPE  
Confirmation No.: 6836  
Atty Docket No.: KANIA-05

Cincinnati, Ohio

May 21, 2007

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

### **REQUEST FOR CERTIFICATE OF CORRECTION OF PATENT FOR PTO MISTAKES**

It is respectfully requested that a Certificate of Correction be issued for the patent identified in the heading. The patent contains errors that occurred through the fault of the Patent Office as follows:

This request is made under 37 C.F.R. § 1.322 to correct this mistake.

Column 1, line 21, after "specimens" insert --do--.

Column 1, line 22, change ", " to --;--.

Column 2, line 52, after "collection." insert the following paragraphs:

--Witold Slowko described in his article in International Symposium "Ion Implantation and other Applications of Ions and Electrons - Ion 2000" a secondary electron detector with a micro-porous plate for environmental scanning electron microscope (SEM), in which he used a micro-porous plate as a diaphragm having a high resistance to a transmission of gas and low resistance to a transmission of electrons. A micro-porous plate could have been a micro channel plate or a micro sphere plates. Micro channels are channels with a diameter approximately 0,01 mm and length 0,5 to 1 mm, what gives the diameter to length ratio 1 : 50 to 1 : 100.

The disadvantage of such micro channels is above all their very low life expectancy in an environmental SEM, as the micro channels are typically within a few hours so contaminated that they are useless for the purpose for which they were intended in an environmental SEM. Another disadvantage is that they put through a big portion of the backscattered electrons, what has a deteriorating effect on a resolving power of the SEM.--

Column 3, line 4, after "connected." insert the following paragraph:

--The low resistance to a transmission of electrons is achieved by electron microlenses inside and in front of each orifice in said diaphragm. Electron microlenses are created by an electrical field protruding through the orifices in said diaphragm. This electrical field originates from a conductive coating inside of the detector chamber that is connected to a voltage source.--

Column 6, line 66, after "diaphragm" delete --being--.

In accordance with the established procedure for handling such certificates a Form PTO-1050 is enclosed herewith listing the error.

Should any additional fees be required, authorization is hereby given to charge such fees to deposit account 23-3000.

Respectfully submitted,

WOOD, HERRON & EVANS, L.L.P

/William R. Allen/

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**UNITED STATES PATENT AND TRADEMARK OFFICE  
CERTIFICATE OF CORRECTION**

Page 1 of 1

PATENT NO. : 7,193,222  
APPLICATION NO.: 10/518,660  
ISSUE DATE : 03/20/2007  
INVENTOR(S) : Jacka et al.

It is certified that an error appears or errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Column 1:

Line 21, after "specimens" insert --do--.  
Line 22, change ", " to --;--.

Column 2, line 52, after "collection." insert the following paragraphs:

--Witold Slowko described in his article in International Symposium "Ion Implantation and other Applications of Ions and Electrons - Ion 2000" a secondary electron detector with a micro-porous plate for environmental scanning electron microscope (SEM), in which he used a micro-porous plate as a diaphragm having a high resistance to a transmission of gas and low resistance to a transmission of electrons. A micro-porous plate could have been a micro channel plate or a micro sphere plates. Micro channels are channels with a diameter approximately 0,01 mm and length 0,5 to 1 mm, what gives the diameter to length ratio 1 : 50 to 1 : 100.

The disadvantage of such micro channels is above all their very low life expectancy in an environmental SEM, as the micro channels are typically within a few hours so contaminated that they are useless for the purpose for which they were intended in an environmental SEM. Another disadvantage is that they put through a big portion of the backscattered electrons, what has a deteriorating effect on a resolving power of the SEM.--

Column 3, line 4, after "connected." insert the following paragraph:

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Column 6, line 66, after "diaphragm" delete --being--.

MAILING ADDRESS OF SENDER (Please do not use customer number below):

441 Vine Street  
Suite 2700  
Cincinnati, OH 45202

This collection of information is required by 37 CFR 1.322, 1.323, and 1.324. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 1.0 hour to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: **Attention Certificate of Corrections Branch, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.**

*If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.*

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6. A record in this system of records may be disclosed, as a routine use, to another federal agency for purposes of National Security review (35 U.S.C. 181) and for review pursuant to the Atomic Energy Act (42 U.S.C. 218(c)).
7. A record from this system of records may be disclosed, as a routine use, to the Administrator, General Services, or his/her designee, during an inspection of records conducted by GSA as part of that agency's responsibility to recommend improvements in records management practices and programs, under authority of 44 U.S.C. 2904 and 2906. Such disclosure shall be made in accordance with the GSA regulations governing inspection of records for this purpose, and any other relevant (i.e., GSA or Commerce) directive. Such disclosure shall not be used to make determinations about individuals.
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